IN-SEASON USE OF TEMIK FOR INSECT MANAGEMENT IN COTTON

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Abstract

Trials were conducted during 2008 and 2009 to evaluate side dress applications of Temik to field borders for tarnished plant bug management. During 2008, trends for lower plant bug numbers and significantly lower plant bug numbers were observed for plots that received Temik. There were trend for higher yields and significantly higher yields observed at some sample locations within the Temik treated plots. Across all sample locations within plots, the plots treated with Temik produced significantly more yield compared to the non-treated plots. During 2009, plant bug numbers were lower compared to 2008. Few differences in plant bug numbers were observed during 2009. Yield analysis for 2009 has not been completed and is not included in this report.

Introduction

The tarnished plant bug, *Lygus lineolaris* (Palisot de Beauvois), has become a major pest of cotton within the Mid-South region over the last several years. The tarnished plant bug has become the target of more insecticide applications than any other insect the Mid-South (Williams 2008) with some growers making up to 15 foliar insecticide applications for plant bug control. Furthermore, tarnished plant bug is becoming resistant to many of the products currently used for control, with few if any replacements expected in the near future (, Hollingsworth et al. 1997, Holloway et al. 1998, Snodgrass and Scott 1988, Snodgrass 1994, Snodgrass and Elzen 1995, Snodgrass 2006). Because current plant bug management practices are not sustainable, additional management alternatives need to be examined.

The tarnished plant bug is a highly polyphagous insect, feeding on over 300 wild and cultivated host plants (Snodgrass et al. 1984). It feeds primarily when plants are flowering, so movement between host plants is common. One of the major plant bug hosts just prior to cotton flowering is field corn. With changing economics, corn has become a more prominent crop in the Mid-South, so the number of cotton-corn interfaces has greatly increased over the last several years. A common observation of these corn-cotton interfaces is that plant bug damage to cotton plants is often more severe in areas adjacent to corn fields compared to cotton plants farther from this interface. While some of this effect may be due to poor insecticide coverage at the field margin, there is evidence that

Materials and Methods

Across LA, AR, MS, TN, and MO trials were conducted during 2008 (nine trials) and 2009 (ten trials) to evaluate the impact of in-season application of aldicarb on tarnished plant bug infestations and yield. Selected sites were fields with a corn-cotton interface with cotton rows running parallel to the corn. Corn and cotton fields were not separated by more than 40 feet of uncultivated land (turn-row, ditch, etc.). The trials included 2 treatments (Temik 15G and a non-treated control) that were applied in addition to all normal production practices. Temik was applied to the first 32 rows from the edge of the field next to corn at 10 lb form. /acre as a side-band when plants in the adjacent corn field were at the green silk stage or the cotton had reached the match-head square stage. When the Temik was applied, the applicator was passed through the non-treated plots so that any root pruning that occurred during application would be uniform across plots for both treatments. Plots were at least 100 ft. long, with a minimum of three replications. All of the plots within a trial were ordered along the corn–cotton interface using a randomized complete block design. With the exception of the Temik applications, the fields were managed according to the growers' standard production practices, including insecticide applications over the entire field.

Sampling for tarnished plant bugs was initiated at the time of Temik application and collected weekly for 4-6 weeks. Sweep net sampling was used throughout the trial to monitor plant bug densities. Drop cloth sampling was also conducted to monitor the level of reproduction in the trial area. Four samples were collected within each plot at regular distances from the edge of the field. Plots were divided into 8 row sections (rows 1-8, 9-16, 17-24, and 25-32) and the center two rows of each section was sampled. Sampled areas were marked so that the same areas could be re-sampled each week. In addition, at least two samples per plot were collected; one was within 4 rows of the plot (35-36 rows from the edge of the field) and the other was at least 150 ft (ca. row 80) out from the edge of the plots to evaluate the width of the elevated TPB density edge. Each sample consisted of 2 sets of 25 sweeps and 2 drop cloth samples (10 row ft). Yield was estimated by harvesting at-least two rows from each set of 8 rows of each plot (4 yield measurements per plot). Also, yield was estimated within the first six rows adjacent to each plot and at 150 ft from the edge of each plot. Data were combined across locations and subjected to ANOVA procedures using the SAS mixed procedure, with means separated according to Fisher's Protected LSD.

Results

During 2008, trends for lower total tarnished plant bug densities using sweep net sampling were observed in the Temik treated plots at all sample locations during the first three weeks after application. Significantly more plant bugs were captured in the non-treated plots compared to the Temik plots at rows 1-8 during week 3, rows 17-24 and rows 25-32 during week 2, and rows 9-16 during week 5 (Table 1). Across all rows, the Temik treated plots had significantly fewer plant bugs than the non-treated plots during weeks 2, 3, and 5 (Table 2).

Trends for lower numbers of total tarnished plant bugs were observed in the Temik treated plots at all sampling locations during the first three weeks after application using drop cloth sampling. Plots treated with Temik had significantly fewer plant bugs than the non-treated plots at rows 1-8 during weeks 2 and 5, rows 9-16 and rows 17-24 during week 3, and rows 25-32 during week 2 (Table 3). Across all rows, the Temik treated plots had significantly fewer plant bugs than the non-treated plots during weeks 2, 3, and 5 (Table 4).

At all sample locations, trends for higher yields were observed in the Temik treated plots compared to the nontreated plots. The sample locations, rows 9-16 and 17-24, in the Temik treated plots produced significantly more yield compared to the same locations in the non-treated plots (Table 5). Also, the sample locations 150 ft outside of the Temik plots yielded significantly more than the same sample locations adjacent to the non-treated plots. Across all rows the Temik treated plots produced significantly more yield compared to the non-treated plots (Figure 1).

C		Total Tari	nished Plant Bugs ¹ /2	25 Sweeps	
Rows/Treatment	Week 1 ²	Week 2 ²	Week 3 ²	Week 4 ²	Week 5 ²
Rows 1-8 ³					
Temik	1.9	3.1	2.6b	1.7	0.7
Non-Treated	2.2	3.5	3.9a	1.8	0.7
P > F	0.91	0.55	< 0.01	0.72	0.87
Rows 9-16 ⁴					
Temik	1.5	2.2	2.5	1.8	0.8b
Non-Treated	2.0	2.6	3.2	1.5	2.2a
P > F	0.28	0.38	0.16	0.41	0.02
Rows 17-24 ⁵					
Temik	1.8	1.6b	2.3	1.5	0.6
Non-Treated	2.5	3.0a	2.7	1.3	0.7
P > F	0.44	< 0.01	0.14	0.42	0.89
Rows 25-32 ⁶					
Temik	1.4	2.0b	2.5	1.1	0.7b
Non-Treated	2.2	3.4a	2.8	0.9	1.6a
P > F	0.53	< 0.01	0.40	0.50	0.05
3 Rows Outside ⁷					
Temik	1.7	2.4	2.9	0.8	0.6
Non-Treated	2.3	2.8	2.5	0.6	0.3
P > F	0.79	0.33	0.28	0.49	0.35
150 ft Outside ⁸					
Temik	1.4	2.7	2.0	0.9	0.2
Non-Treated	2.0	2.5	1.8	0.9	0.3
P > F	0.29	0.25	0.55	0.92	0.56

Table 1. Impact of side dress application of Temik 15G on tarnished plant bug densities sampled by sweep net during 2008.

¹Adults plus nymphs.

²Weeks after application.

³Rows 1-8 from interface with corn.

⁴Rows 9-16 from interface with corn.

⁵Rows 17-24 from interface with corn.

⁶Rows 25-32 from interface with corn.

⁷3 rows outside of and adjacent to the treated and non-treated plots.

⁸150 feet outside of and adjacent to the treated and non-treated plots.

Table 2. Impact of side dress application of Temik 15G on tarnished plant bug densities across rows sampled by sweep net during 2008.

_	Total Tarnished Plant Bugs ¹ /25 Sweeps						
Rows/Treatment	Week 1 ²	Week 2 ²	Week 3 ²	Week 4 ²	Week 5 ²		
Temik	1.6	2.2b	2.5b	1.5	0.7b		
Non-Treated	2.2	3.1a	3.1a	1.3	1.3a		
P > F	0.36	< 0.01	< 0.01	0.40	0.01		

Means with a common letter are not significantly different (FPLSD, P=0.05).

¹Adults plus nymphs.

		Total Tar	nished Plant Bugs ¹ /	5 row feet	
Rows/Treatment	Week 1 ²	Week 2 ²	Week 3 ²	Week 4 ²	Week 5 ²
Rows 1-8 ³					
Temik	0.7	1.9b	2.5	1.6	0.6b
Non-Treated	0.3	3.2a	3.1	1.9	1.7a
P > F	0.20	< 0.01	0.18	0.62	0.02
Rows 9-16 ⁴					
Temik	0.2	2.0	2.1b	2.1	0.7
Non-Treated	0.2	2.7	4.4a	1.9	1.5
P > F	0.99	0.13	< 0.01	0.74	0.19
Rows 17-24 ⁵					
Temik	0.2	1.6	2.5b	1.4	0.5
Non-Treated	0.3	2.3	3.5a	1.5	1.1
P > F	0.78	0.14	0.04	0.73	0.27
Rows 25-32 ⁶					
Temik	0.8	1.5b	2.7	1.9	0.3
Non-Treated	0.5	2.7a	3.6	1.9	1.5
P > F	0.29	< 0.01	0.08	0.94	0.09
3 Rows Outside ⁷					
Temik	0.5	3.0b	3.0	1.1	0.3
Non-Treated	0.9	2.5a	4.3	1.4	0.4
P > F	0.11	0.03	0.12	0.53	0.55
150 ft Outside ⁸					
Temik	0.5	2.2	3.3	1.3	0.3
Non-Treated	0.7	2.3	3.5	1.0	0.4
P > F	0.66	0.77	0.67	0.39	0.63

Table 3. Impact of side dress application of Temik 15G on tarnished plant bug densities sampled by drop cloth during 2008.

¹Adults plus nymphs.

²Weeks after application.

³Rows 1-8 from interface with corn.

⁴Rows 9-16 from interface with corn.

⁵Rows 17-24 from interface with corn.

⁶Rows 25-32 from interface with corn.

⁷3 rows outside of and adjacent to the treated and non-treated plots.

⁸150 feet outside of and adjacent to the treated and non-treated plots.

Table 4. Impact of side dress application of Temik 15G on tarnished plant bug densities across rows sampled by drop cloth during 2008.

	Total Tarnished Plant Bugs ¹ /5 row ft						
Rows/Treatment	Week 1 ²	Week 2 ²	Week 3 ²	Week 4 ²	Week 5 ²		
Temik	0.5	1.8b	2.6a	1.7	0.5b		
Non-Treated	0.3	2.8a	3.6b	1.8	1.4a		
P > F	0.34	< 0.01	< 0.01	0.72	< 0.01		

Means with a common letter are not significantly different (FPLSD, P=0.05).

¹Adults plus nymphs.

	Yield (lb lint/acre)						
Treatment	Rows 1-8 ¹	Rows $9-16^2$	Rows 17-24 ³	Rows 25-32 ⁴	6 Rows Outside ⁵	150 ft Outside ⁶	
Temik	904.3	916.9a	929.5a	938.9	1,018.5	1,047.9a	
Non-Treated	826.5	826.8b	837.8b	884.7	961.6	952.8b	
P > F	0.21	0.05	0.01	0.16	0.16	< 0.01	

Table 5. Impact of side dress application of Temik 15G on lint yield during 2008.

¹Rows 1-8 from interface with corn.

²Rows 9-16 from interface with corn.

³Rows 17-24 from interface with corn.

⁴Rows 25-32 from interface with corn.

⁵6 rows outside of and adjacent to the treated and non-treated plots.

⁶150 feet outside of and adjacent to the treated and non-treated plots.

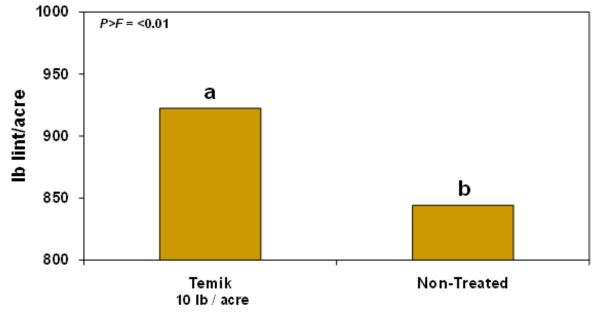


Figure 1. Impact of side dress application of Temik 15G on lint yield across rows during 2008.

During 2009, tarnished plant bug densities were lower than that observed during 2008. Trends for lower numbers of total plant bugs using sweep net sampling were observed at all sample locations during weeks 2 and 3 after application. Significantly fewer plant bugs were observed in the Temik treated plots compared to the non-treated plots at rows 1-8 and 17-24 during week 2 (Table 6). Across rows, plots treated with Temik had significantly fewer plant bugs compare to the non-treated plots during weeks 2 and 5 (Table 7).

Using drop cloth sampling, there were no significant differences in numbers of total tarnished plant bugs at any sample location during any week (Table 8) or across sample locations during any week (Table 9).

At the sample locations, rows 9-16 and 25-32, in the Temik treated plots there were trends for higher yields compared to the same locations in the non-treated plots (Table 10). Also, at the sample locations rows 17-24 the Temik plots yielded significantly more than the same sample locations in the non-treated plots. Across all rows the Temik treated plots produced significantly more yield compared to the non-treated plots (Figure 2).

		Total Tar	nished Plant Bugs ¹ /2	25 Sweeps	
Rows/Treatment	Week 1 ²	Week 2 ²	Week 3 ²	Week 4 ²	Week 5 ²
Rows 1-8 ³					
Temik	0.8	1.4b	2.0	2.0	1.6
Non-Treated	0.9	2.1a	2.6	2.2	2.6
P > F	0.71	0.03	0.14	0.44	0.25
Rows 9-16 ⁴					
Temik	0.8	1.7	2.5	1.8	1.1
Non-Treated	0.8	2.2	2.7	2.0	1.9
P > F	0.85	0.15	0.76	0.60	0.12
Rows 17-24 ⁵					
Temik	0.9	1.5b	1.5	1.7	0.9
Non-Treated	0.9	2.0a	2.2	2.0	1.8
P > F	0.74	0.03	0.20	0.37	0.07
Rows 25-32 ⁶					
Temik	0.7	1.5	1.9	2.0	1.0
Non-Treated	1.1	1.8	2.2	1.9	2.4
P > F	0.14	0.25	0.49	0.81	0.05
3 Rows Outside ⁷					
Temik	1.0	1.5	2.2	1.8	1.2
Non-Treated	0.8	1.8	2.5	1.8	2.3
P > F	0.25	0.36	0.42	0.88	0.21
150 ft Outside ⁸					
Temik	0.7	1.5	1.1	1.2	1.9
Non-Treated	0.8	1.9	1.3	1.0	2.8
P > F	0.51	0.35	0.68	0.58	0.27

Table 6. Impact of side dress application of Temik 15G on tarnished plant bug densities sampled by sweep net during 2009.

¹Adults plus nymphs.

²Weeks after application.

³Rows 1-8 from interface with corn.

⁴Rows 9-16 from interface with corn.

⁵Rows 17-24 from interface with corn.

⁶Rows 25-32 from interface with corn.

⁷3 rows outside of and adjacent to the treated and non-treated plots.

⁸150 feet outside of and adjacent to the treated and non-treated plots.

Table 7. Impact of side dress application of Temik 15G on tarnished plant bug densities across rows sampled by sweep net during 2009.

	Total Tarnished Plant Bugs ¹ /25 Sweeps					
Rows/Treatment	Week 1 ²	Week 2 ²	Week 3 ²	Week 4 ²	Week 5 ²	
Temik	0.8	1.5b	2.0	1.9	1.1b	
Non-Treated	0.9	2.0a	2.4	2.0	2.2a	
P > F	0.19	< 0.01	0.6	0.41	< 0.01	

Means with a common letter are not significantly different (FPLSD, P=0.05).

¹Adults plus nymphs.

		Total Tar	nished Plant Bugs ¹ /:	5 row feet	
Rows/Treatment	Week 1 ²	Week 2 ²	Week 3 ²	Week 4 ²	Week 5 ²
Rows 1-8 ³					
Temik	0.8	1.4	1.0	2.2	3.0
Non-Treated	1.5	1.7	1.3	1.8	3.5
P > F	0.34	0.43	0.09	0.43	0.57
Rows 9-16 ⁴					
Temik	0.5	0.9	1.1	2.2	2.1
Non-Treated	0.9	0.8	1.4	2.7	3.0
P > F	0.06	0.93	0.38	0.26	0.25
Rows 17-24 ⁵					
Temik	0.3	1.0	1.0	1.7	2.0
Non-Treated	0.5	1.5	1.0	2.3	2.5
P > F	0.18	0.20	0.85	0.07	0.53
Rows 25-32 ⁶					
Temik	0.5	1.0	1.7	1.9	1.9
Non-Treated	0.6	1.1	1.4	2.4	2.5
P > F	0.72	0.72	0.42	0.35	0.43
3 Rows Outside ⁷					
Temik	0.1	0.7	1.1	2.1	3.0
Non-Treated	0.5	0.9	1.0	2.0	4.2
P > F	0.06	0.60	0.61	0.84	0.16
150 ft Outside ⁸					
Temik	0.0	0.4	0.6	1.6	2.5
Non-Treated	0.0	0.3	0.9	1.6	2.4
P > F	0.99	0.64	0.13	0.89	0.92

Table 8. Impact of side dress application of Temik 15G on tarnished plant bug densities sampled by drop cloth during 2009.

¹Adults plus nymphs.

²Weeks after application.

³Rows 1-8 from interface with corn.

⁴Rows 9-16 from interface with corn.

⁵Rows 17-24 from interface with corn.

⁶Rows 25-32 from interface with corn.

⁷3 rows outside of and adjacent to the treated and non-treated plots.

⁸150 feet outside of and adjacent to the treated and non-treated plots.

Table 9. Impact of side dress application of Temik 15G on tarnished plant bug densities across rows sampled by drop cloth during 2009.

		Total Ta	rnished Plant Bugs ¹	/5 row ft	
Rows/Treatment	Week 1 ²	Week 2 ²	Week 3 ²	Week 4 ²	Week 5 ²
Temik	0.5	1.1	1.2	2.0	2.3
Non-Treated	0.9	1.3	1.3	2.3	2.8
P > F	0.10	0.37	0.75	0.23	0.13

Means with a common letter are not significantly different (FPLSD, P=0.05).

¹Adults plus nymphs.

	Yield (lb lint/acre)						
Treatment	Rows 1-8 ¹	Rows 9-16 ²	Rows 17-24 ³	Rows 25-32 ⁴	6 Rows Outside ⁵	150 ft Outside ⁶	
Temik	875.6	828.6	953.4a	863.4	802.4	856.7	
Non-Treated	855.8	771.1	835.0b	799.2	789.7	877.2	
P > F	0.56	0.12	0.03	0.17	0.66	0.68	

Table 10. Impact of side dress application of Temik 15G on lint yield during 2009.

¹Rows 1-8 from interface with corn.

²Rows 9-16 from interface with corn.

³Rows 17-24 from interface with corn.

⁴Rows 25-32 from interface with corn.

⁵6 rows outside of and adjacent to the treated and non-treated plots.

⁶150 feet outside of and adjacent to the treated and non-treated plots.

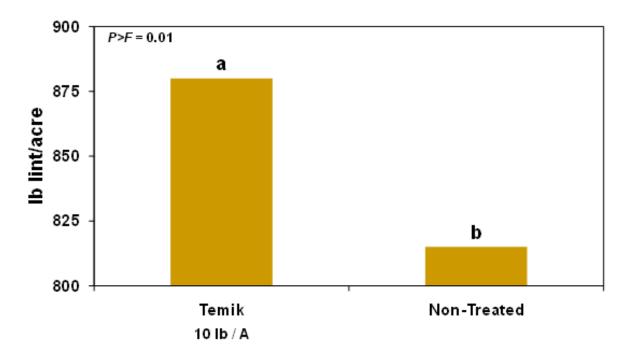


Figure 2. Impact of side dress application of Temik 15G on lint yield across rows during 2009.

Summary

During 2008, trends for reduced plant bug numbers and significantly lower plant bug numbers were observed in the plots treated with Temik. Also, trends for higher yields and significantly higher yields were observed in the Temik treated plots compared to the non-treated plots. Across all sample locations within plots, Temik resulted in significantly greater yield compared to the non-treated control. During 2009, plant bug densities were lower than those observed during 2008. Trends for lower plant bug numbers were less apparent. Many trial locations experienced excessive rainfall through much of the sampling and boll maturation periods during 2009. The trends for higher yields with the use of Temik were not as apparent during 2009 as those during 2008. However, across sample locations the Temik treated plots did produce significantly higher yields than the non-treated plots. In many areas of the Mid-South, severe tarnished plant bug injury to cotton is observed along field margins adjacent to other crops and non-crop areas. This management practice has potential to help manage tarnished plant bug at these field interfaces.

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